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Assessing Side-Channel Leakages

Simulating Traces with Open-Source Tools

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Hardware masking against side-channel attacks

Let us consider **secret** data, such as the private key.

Masking¹ divides the **secret** into various random shares.

After computing, we can combine the shares to reveal the **secret**.



secret ← the private key

share_1 ← random
share_2 ← secret ⊕ share_1



+ Masking is a strong countermeasure against side-channel attacks.

- + The security increases exponentially with each additional share.
- + To reveal the secret, it is ideal to possess knowledge of all the shares.
- While the principle may seem simple and effective, the practical implementation of masking can be complex and challenging.

It is not straightforward.



The design process may introduce side-channel vulnerabilities.

L. Goubin et al. "DES and Differential Power Analysis (The "Duplication" Method)". In CHES 1999.

The Trichina's multiplication gadget¹

To protect A and B, they are each divided into two shares, (a_0, a_1) and (b_0, b_1) , and an additional random bit, r, is needed for the process.



¹ E. Trichina. "Combinational Logic Design for AES SubByte Transformation on Masked". In IACR Cryptol. ePrint 2003.

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Masking security verification processes

Verification of theoretic security levels may not be feasible in certain cases.

Manual verification is both prone to errors and time-consuming, thereby posing a challenge for scaling up to larger systems.

Gadget-level verification tools have limited capability to assess the security of complex systems, such as algorithmic masking. Pre-silicon leakage

assessment

Verify information-

theoretic conditions

Manufacturing



EDA tools provide a range of features and functionalities to assess the side-channel leakages of masking implementations.

Post-silicon validation



Summary



Physical hazards – e.g., glitches – are source of exploitable side-channel leakages¹.



The shares must be statistically independent to compose several masked sub-blocks effectively.



An inaccurate leakage model may result in vulnerable designs.



Verifying security on complex systems with algorithmic-level hardware masking can be challenging.



How to evaluate the security of complex masking implementations using (open-source) EDA tools ?



S. Mangard et al. "Side-Channel Leakage of Masked CMOS Gates". In CR-RSA 2005.







Logic simulation

Icarus Verilog Open Source hello.v Terminal > iverilog -o hello hello.v module hello; initial begin > vvp hello \$display("Hello, World"); Hello, World \$finish; end endmodule yes PASS **RTL Files Key applications** Hardware description language compiler. Icarus ٠ correct? Verilog Logic simulation with VPI. • Behavioral validation. ٠ Testbench FAIL no S. Williams. "The ICARUS Verilog Compilation". In GitHub: Icarus Verilog 8

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Verilog RTL synthesis

Yosys Open Synthesis Suite



Key applications

- Process almost any synthesizable Verilog-2005 design.
- Mapping to ASIC standard cell libraries.
- Design reports.



read design
read_verilog mydesign.v

generic synthesis
synth -top mytop

mapping library cells
dfflibmap -liberty mycells.lib
abc -liberty mycells.lib
clean

write synthesized design
write_verilog synth.v

Open Source



C. Wolf. "Yosys Open SYnthesis Suite". In https://yosyshq.net/yosys/

Static Timing Analysis (STA)

OpenSTA: Parallax Static Timing Analyzer



Key applications

- Verify the timing of a design using standard file formats.
- Generate gate-level delay files (SDF).
- Timing reports.



read library cells
read_liberty mycells.lib

read design
read_verilog mydesign.v
link_design mydesign
create_clock -period 10 clock_i

report timing
report_checks > timing.log

write sdf file
write_sdf mydesign.sdf

Open Source



J. Cherry. "OpenSTA: Parallax Static Timing Analyzer". In GitHub: OpenSTA



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Gate-level simulation with open-source tools

SDF back-annotation is necessary to take glitches into account.



Hence, we rely on commercial tools for this gate-level task.



Gate-level verification

Gate-level simulation with back-annotated delay



Key applications

- SDF back-annotation.
- Post-synthesis verification.
- VCD generation.

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device_tb.v

module device_tb; device DUT(...); initial begin \$sdf_annotate("delay.sdf", DUT); end endmodule



Commercial





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The Side-Channel Analysis Library (SCALib)

SCALib: state-of-the-art tools for side-channel evaluation



Key applications

- High performance leakage assessment.
- Metrics, modeling and attacks.
- On-the-fly computation with a streaming API.

from scalib.metrics import Ttest
import numpy as np
traces = open("simulation.traces")
tag = open("metadata.txt")

ttest = Ttest(1000, d=3)
ttest.fit_u(traces, tag)
t = ttest.get_ttest()

plot(t)



Python Package

G. Cassiers and O. Bronchain. "SCALib: A Side-Channel Analysis Library". In GitHub: SCALib 17



The TVLA procedure to identify exploitable side-channel leakages in as masking implementation.



¹ G. Goodwill et al. "A testing methodology for side-channel resistance validation". In NIST Workshop 2011.

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Conclusion and perspectives





Conclusion and perspectives

Simulating Traces with Open-Source Tools.



Pros

- + A (close to) open-source design flow.
 - + Logic simulation with Icarus Verilog or Verilator.
 - + Synthesis with Yosys.
 - + Static timing analysis with OpenSTA.
 - + Open-source libraries Google Skywater 130 nm, FreePDK 45 nm.

Cons

 The gate-level simulation with open-source tools is currently limited due to some issues with the SDF support.

What next?

Implement support for SDF files or consider utilizing commercial tools.

Our technology starts with You



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